

BRUKER NANO ANALYTICS

QUANTAX ED-XS: Cost-Effective Solution for Material Characterization

Laurie Palasse, PhD Global Application Manager

Daniel Goran, PhD Sr. Product Manager EBSD

Bruker Nano Analytics, Berlin, Germany

EBSD



Overview

01 Why EBSD and why integrated with EDS?

02 QUANTAX ED-XS: simplicity enables affordable science!

03 Application examples

04 Summary





01 Why EBSD?

Innovation with Integrity



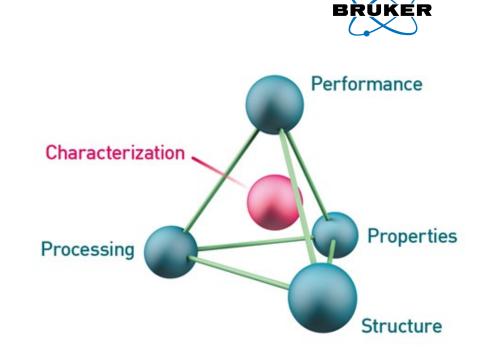
Introduction Why EBSD?

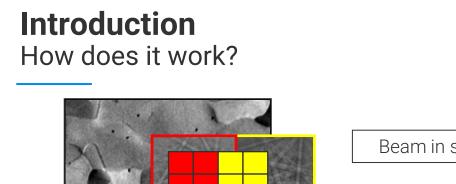
- Understanding the material strength and deformation properties by:
 - Measuring crystal orientation
 - Analyzing the grain structure
 - Identify and Distinguish phases
- Complement the chemical information, maximize your knowledge of the sample and the processes involved
 - Texture analysis: assessing the effects of the thermomechanical processes
 - Control or investigate material properties
 - Process control: Manufacturing, R&D, Pure research
 - Complete other techniques (X-ray diffraction, TEM studies...)

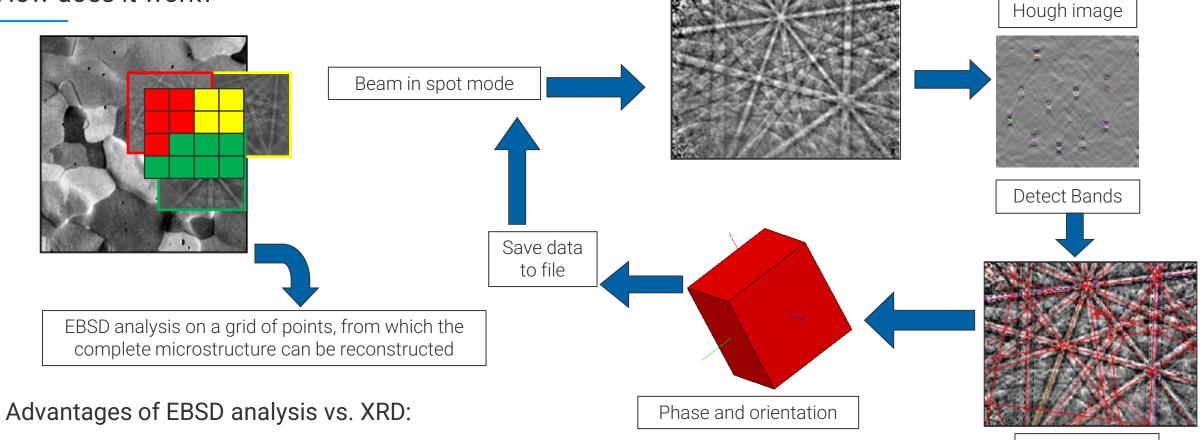
>> Correlates local texture (orientation) with microstructure (grain metrics, GB, ...)

Introduction Why EBSD?

- Processing of metals & alloys
 - Control mechanical properties
 - Reach maximum performance
- Processing optimization:
 - Based on results from mechanical testing (Properties)
 - Iteratively refine processing parameters until desired properties are obtained
 - Little to no understanding of the structural changes happening during processing
 - Based on Structure-Properties relationship, i.e. full understanding of mechanisms involved
 - Correlate structural changes with resulting properties after applying a given thermomechanical process
 - EBSD is one of the few techniques that can help making this correlation
 - EBSD is the only technique enabling correlation between local crystal orientation distribution and microstructure (nano to meso to macro scale):







- corelation between local texture and microstructure
- grain boundary analysis
- grain size & shape analysis

https://www.youtube.com/watch?v=TOGRtACDw7M

Collect EBSP

Index EBSP

6



02 QUANTAX ED-XS



Innovation with Integrity

e-Flash^{xs}

QUANTAX ED-XS The simplest and most affordable solution

Complete integrated EDS and EBSD system:

- eFlashXS
- Xflash® EDS detector 30mm²
- ESPRIT Software platform





QUANTAX ED-XS The simplest and most affordable solution

Main specs:

- Binning capable CMOS camera with 720x540pixels native resolution
- Binning modes: 2x2, 3x3, 4x4, 5x5 and 6x6
- Max speed: 520 frames/second
- Dimensions (outer): L=84mm (3.3in), Φ=48mm (1.9in)
- Weight: ~0.85Kg
- Power and data transfer: 1x USB3.0 cable
- User replaceable phosphor screen
- User removable detector head with slide-in & -out mechanism
- Custom optics system with field lens for maximum light efficiency







QUANTAX ED-XS The simplest and most affordable solution

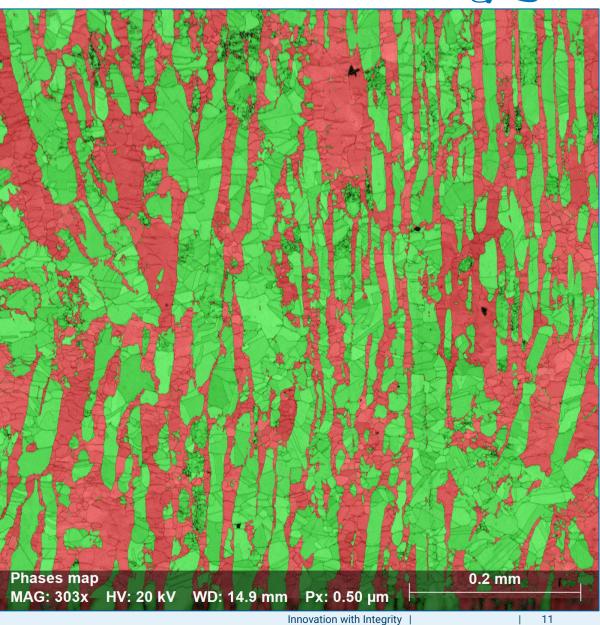
- EBSD detector is static easy to operate
- Automatic gain and no -or little- exposure time adjustment easy to operate
- No pattern center calibration required easy to operate
- Automated crystal phase setup easy to operate
- User replaceable phosphor screen and Field Replacement Unit low downtime
- Automated data saving Prevents data loss
- Automatic "EHT OFF" at the end of map acquisition Saves filament life



Introduction What is EBSD used for?

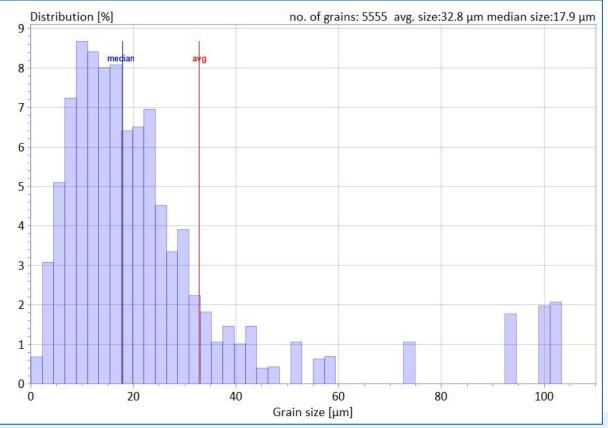
- Quantification of microstructural features:
 - Phase (crystallographic) ratio and spatial distribution
 - 43% Ferrite
 - 57% Austenite

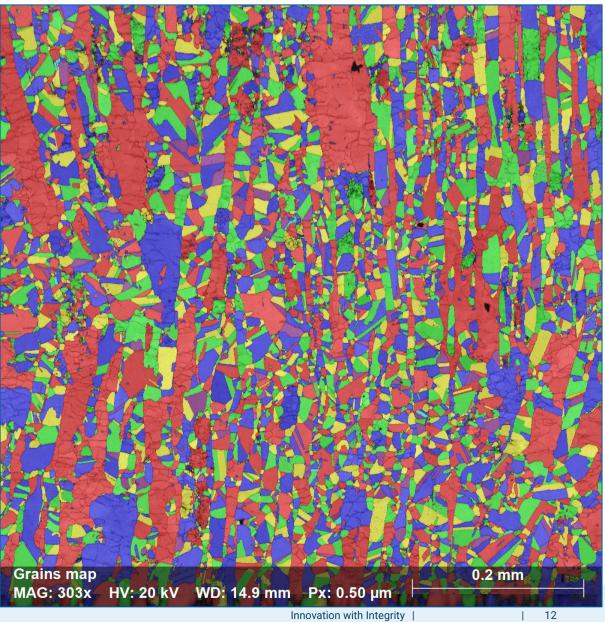
NO DATA CLEANING!!



Introduction What is EBSD used for?

- Quantification of microstructural features:
 - Phase (crystallographic) ratio and spatial distribution
 - Grain size and distribution





Introduction What is EBSD used for?

- Quantification of microstructural features:
 - Phase (crystallographic) ratio and spatial distribution

Iron-alpha

Austenite, fcc (New)

[111]

[111]

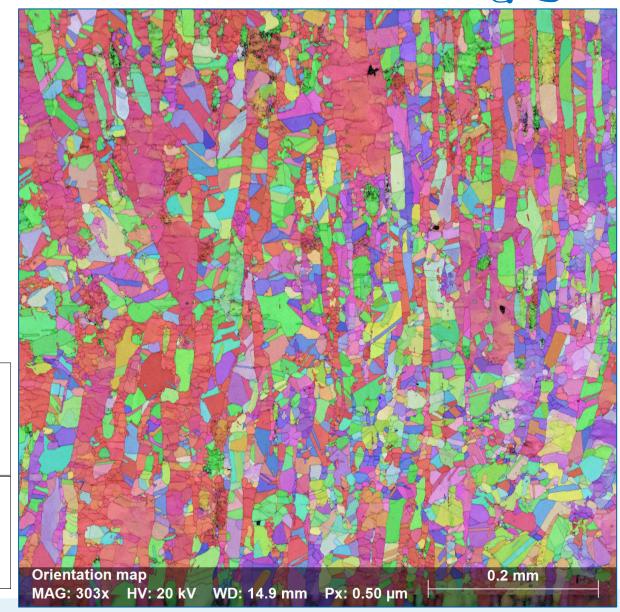
[001]

[101]

[001]

[101]

- Grain size and distribution
- Orientation distribution map



Innovation with Integrity |

Introduction What is EBSD used for?

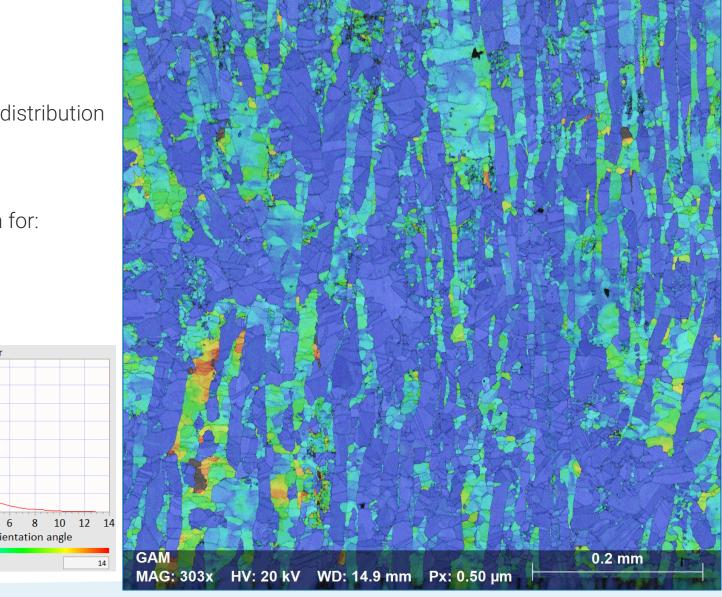
- Quantification of microstructural features:
 - Phase (crystallographic) ratio and spatial distribution

x 1E3 Number

4

Misorientation angle

- Grain size and distribution
- Orientation distribution map
- Grain (and Kernal) Average Misorientation for:
 - Deformation state •
 - Deformed vs. Recrystallized ratio •





03 Application Examples

Innovation with Integrity



Simplicity Delivers Affordable Science Application example

Characterization of microstructural features in stainless steels

Duplex Steel with slightly deformed Ferrite grains

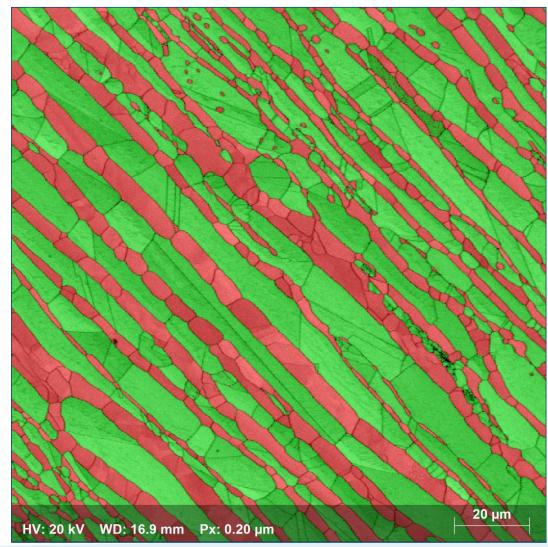
Qualitative & quantitative characterization

Important parameters:

- EHT: 20kV
- Probe current: ~5nA
- Step size: 200nm
- Acquisition speed: 502 frames/second
- Total acquisition time: 16:44 minutes
- Map size: 504k pixels
- Zero solutions: 0.8% NO DATA CLEANING!!
- Phase ratio (normalized):
 - 38% Ferrite
 - 62% Austenite

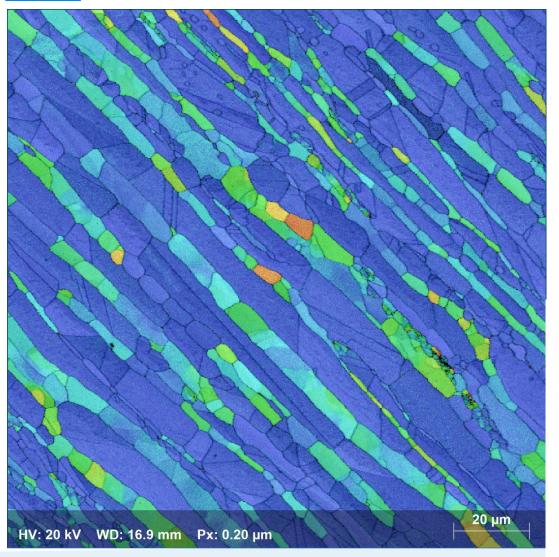
BRUKER

Duplex steel – phase ratio & distribution



© 2024 Bruker

Qualitative & quantitative characterization



Characterization of grain deformation state

x 1E3 Numailmeaverage misorientation

3 4 5 6 7 8 9 10

Misorientation angle

22

20 18 16

0

2

Features:

- Orientation distribution map
- Grain Average Misorientation

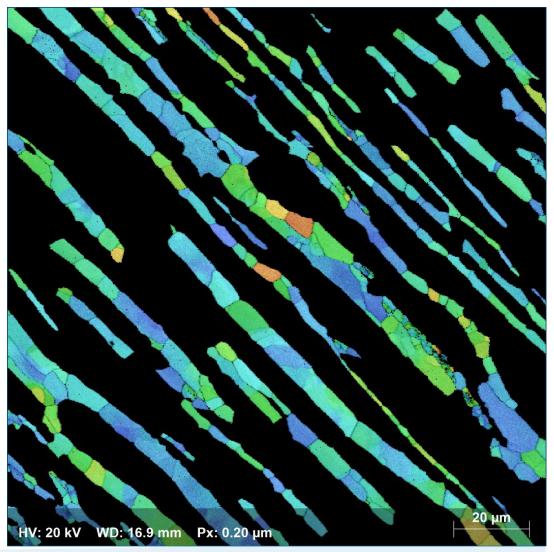
Analysis options:

- Deformation state
- Deformed vs. Recrystallized ratio



18

Qualitative & quantitative characterization



Characterization of grain deformation state

x 1E3 Numaioneaverage misorientation

4 5 6 7

Misorientation angle

8

9 10

0

0

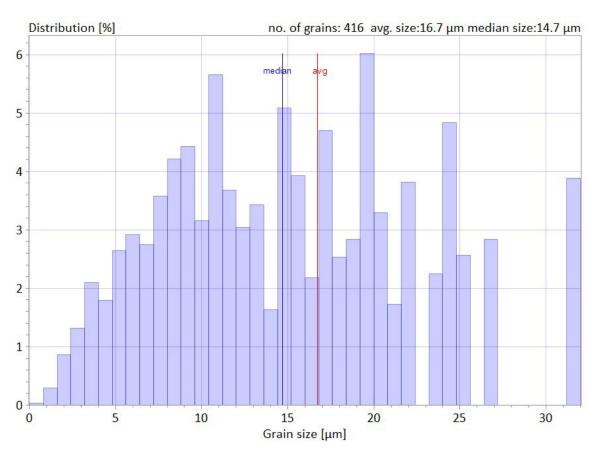
2 3

Features and analysis options:

- GAM map for Austenite grains
- GAM map for Ferrite grains
- Subset of all deformed grains covering 30.2% of field of view

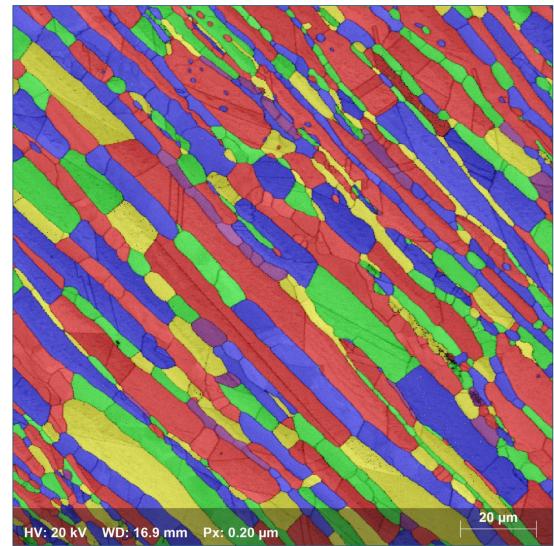
Qualitative & quantitative characterization

Grain size distribution – both phases



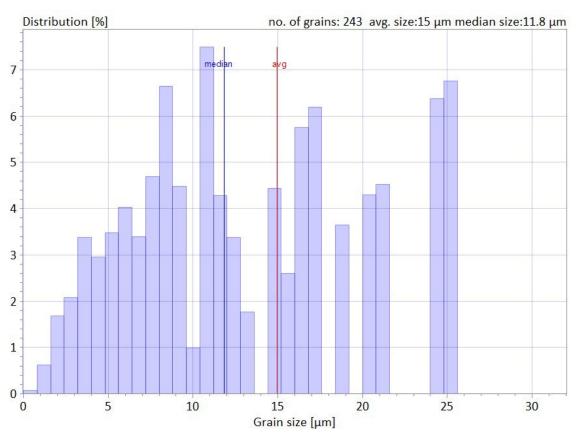
BRUKER

Grains map – grains shown in random colors

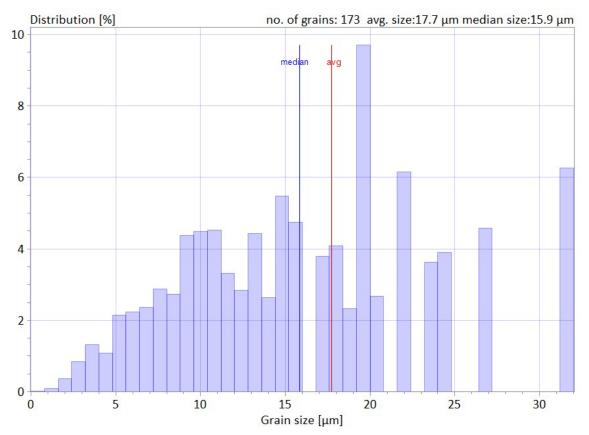


Qualitative & quantitative characterization

Grain size distribution Ferrite





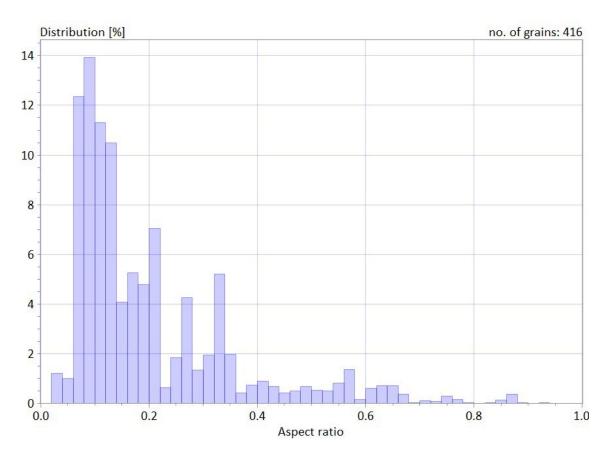


Grain size distribution Austenite

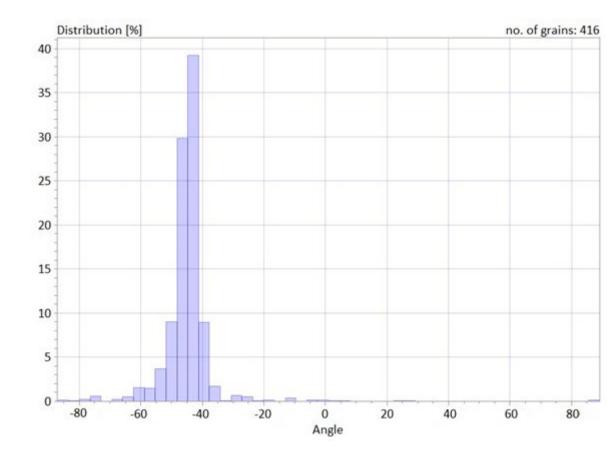
Qualitative & quantitative characterization

BRUKER

Grain shape distribution



Main axis inclination or grain alignment distribution





Simplicity Delivers Affordable Science Application example

High resolution measurements on dual-phase Ti-alloy

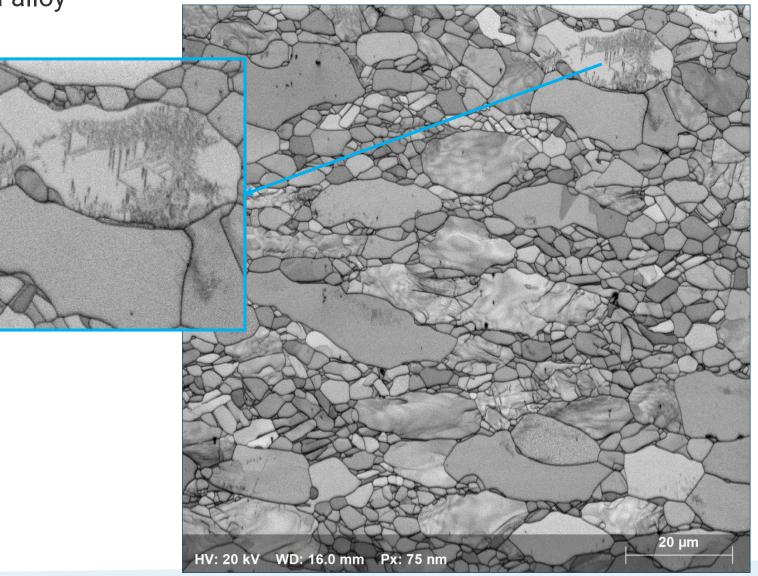


Simplicity Delivers Affordable Science High spatial resolution_ dual-phase Ti-alloy

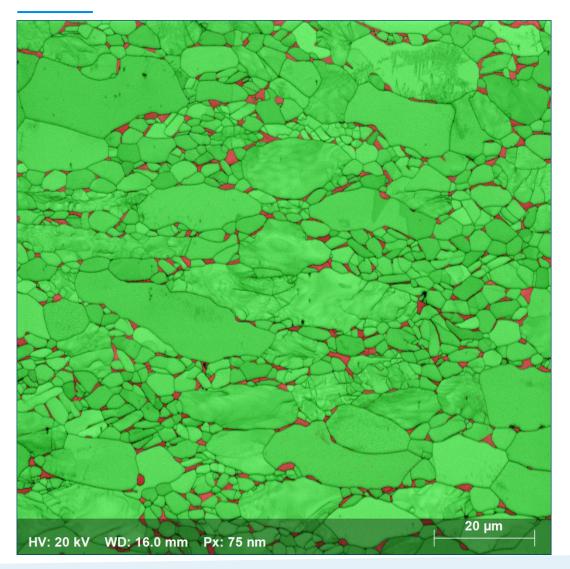
Important parameters:

- EHT: 20kV
- Probe current: ~3 nA
- Step size: 75 nm
- Acquisition speed: >100 fps
- Map size: +2M pixels
- > 1000 grains
- Pattern resolution: 180x135 pixels
- Zero sol.: 1.48 %





Quantitative microstructure characterization_dual-phase Ti-alloy



BRUKER

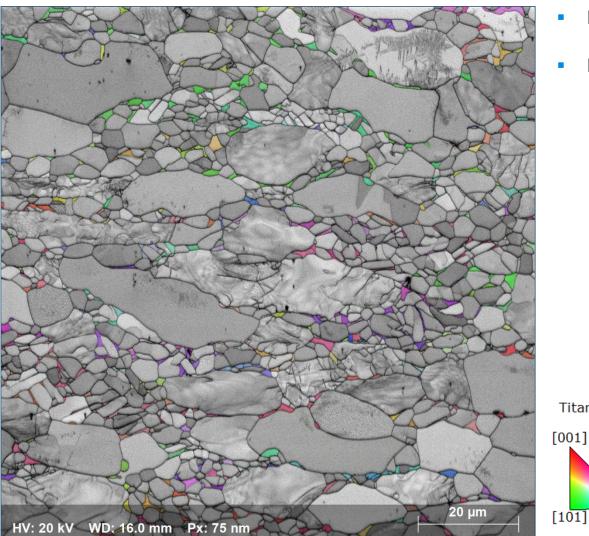
Phase fractions: 94,3% alpha-Ti and 4,22% beta-Ti

Possible subsetting based on:

- Phase
- Pattern quality value
- Crystal orientation (pole figure, texture component)
- GAM and Kernel Average Misorientation (KAM)
- Grain size, shape, main axis inclination

NO DATA CLEANING!!

Quantitative microstructure characterization_dual-phase Ti-alloy



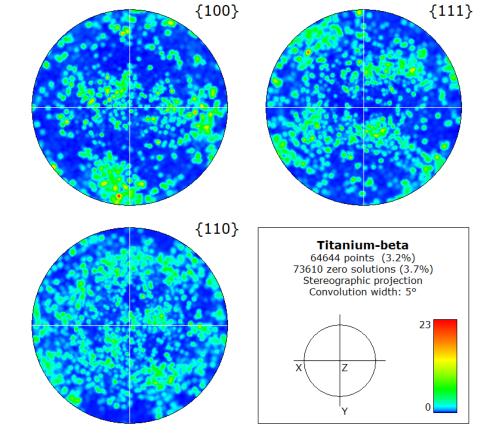


Beta-Ti phase subset

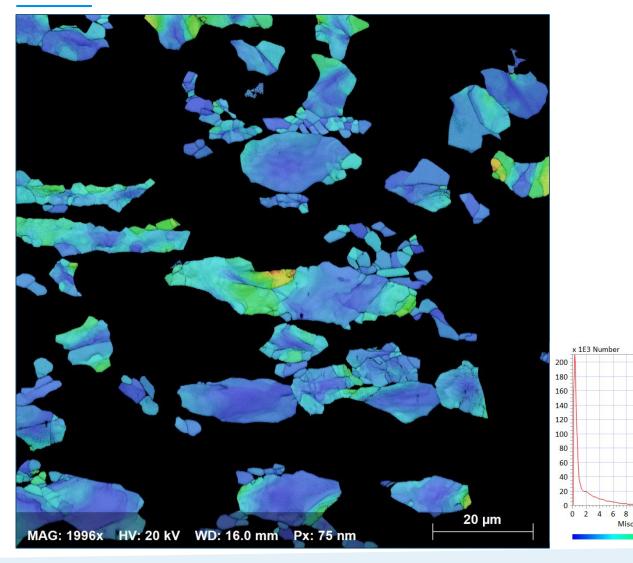
Beta-Ti pole figures

Titanium-beta

[111]



Quantitative microstructure characterization_dual-phase Ti-alloy



BRUKER

Important details:

- No data cleaning applied
- Step size: 75 nm

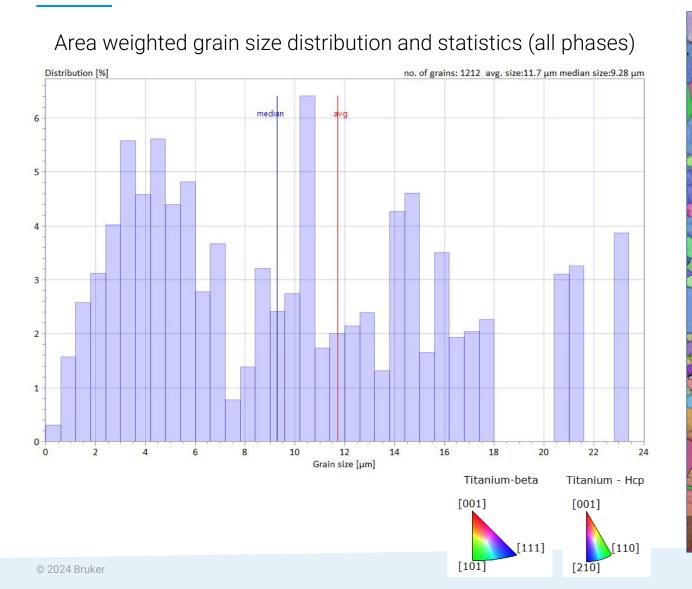
Grain average misorientat

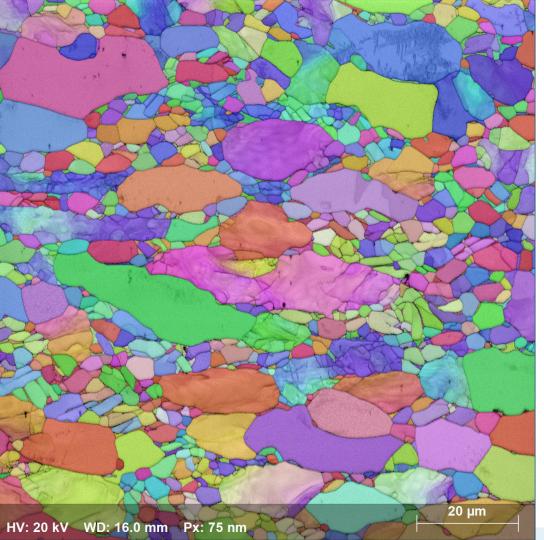
- GAM map showing intragranular plastic deformation
- GAM used for creating subsets
- Deformed grains represent 31.2 % of mapped area

BRUKER

Simplicity Delivers Affordable Science

Quantitative microstructure characterization_dual-phase Ti-alloy



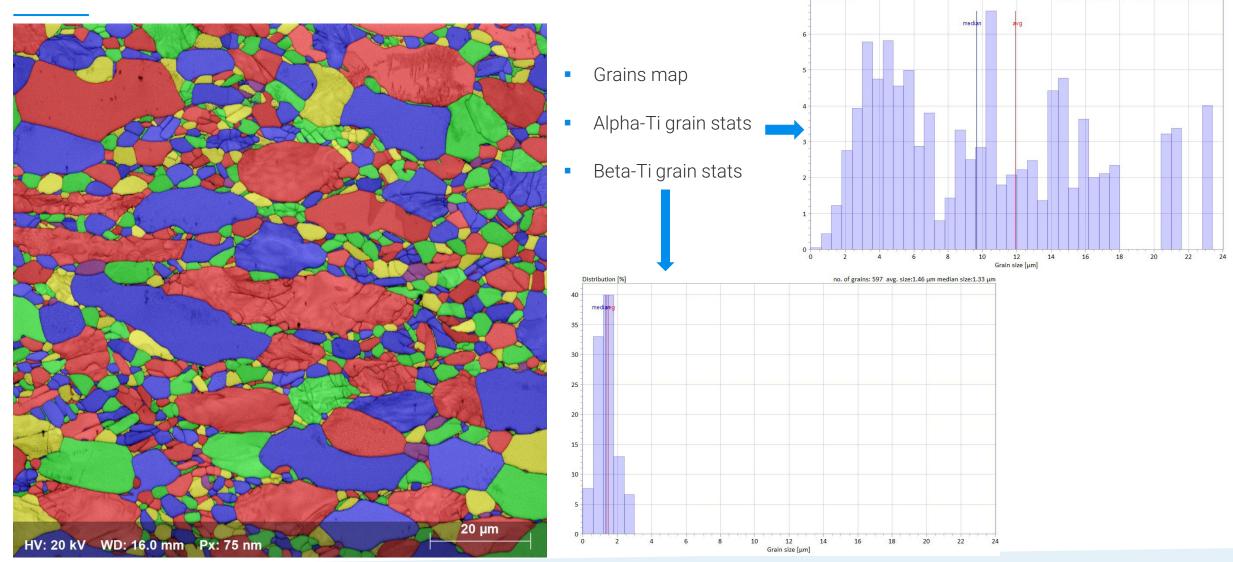


BRUKER

no. of grains: 615 avg. size:11.9 µm median size:9.67 µm

Simplicity Delivers Affordable Science

Quantitative microstructure characterization_dual-phase Ti-alloy



Distribution [%]



Simplicity Delivers Affordable Science Application example

High speed measurements on materials with low electron scattering yield

Amorphous Si film crystallized using a scanning laser beam

Qualitative & quantitative characterization_ Si film

Important parameters:

- EHT: 20kV
- Probe current: ~5nA
- Step size: 0.25 µm
- Acquisition speed: 505 frames/second
- Total acquisition time: 1:06 h
- Map size: ~2M pixels
- Pattern resolution: 144x108 pixels
- Zero sol.: 0.8% (excluding amorphous region)

NO DATA CLEANING!!

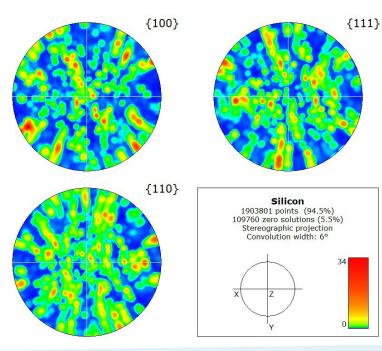
© 2024 Bruker

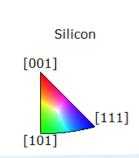


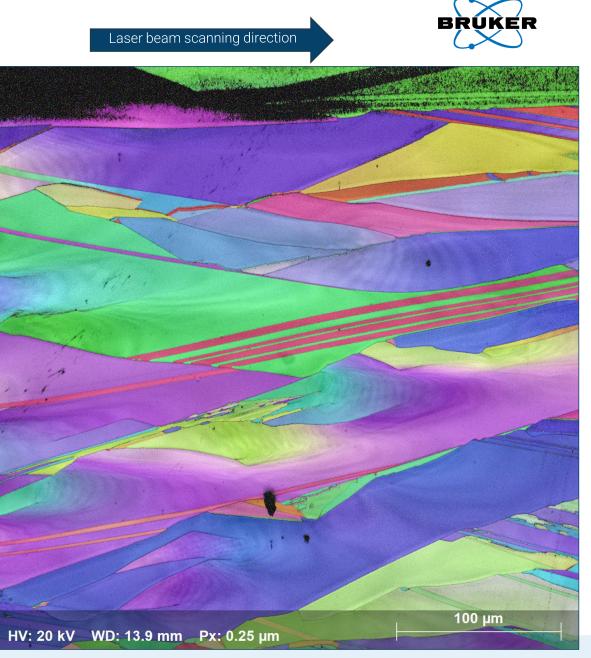


Simplicity Delivers Affordable Science Qualitative & quantitative characterization_ Si film

- Crystal orientation map
 - Fine twin domains
 - Significant lattice rotations across large elongated grains
- Crystallographic texture analysis
 - {110} partial fiber along the laser beam scan direction









Simplicity Delivers Affordable Science Application example

Phase identification and distribution analysis of little-known multi-phase containing materials (applicable to both: materials and earth sciences)

Highly alloyed Fe-Si composite

Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials



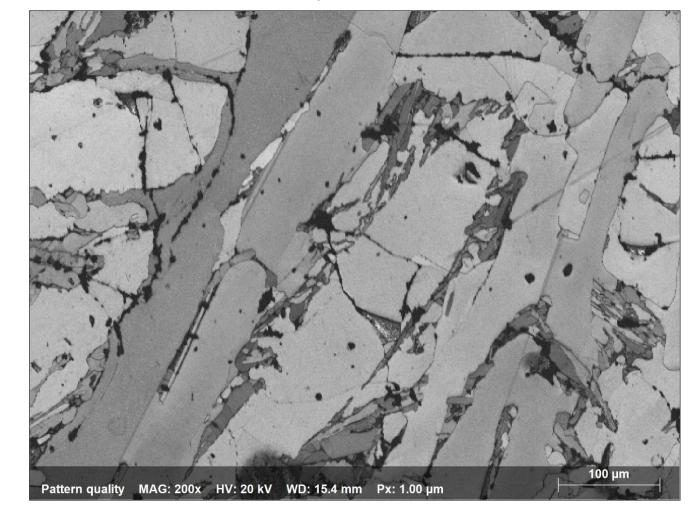
Important parameters:

- EHT: 20kV & Probe current: ~15nA
- Step size: 1µm
- Acquisition speed: 50 points/second
- Total acquisition time: 1:44 hours
- Map size: 309k pixels

Analysis type:

- Phase identification
- Phase distribution
- Phase ratio

Fe-Si composite material



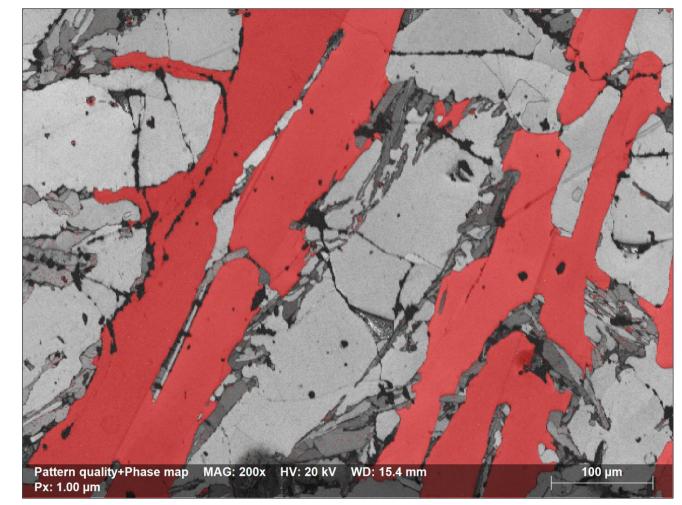
Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials



Important details:

- Simultaneous acquisition of EBSPs and EDS spectra
- Only one phase was used during data acquisition resulting in reduced time to setup measurement
- All other crystallographic phases have been identified offline using Advanced Phase ID feature

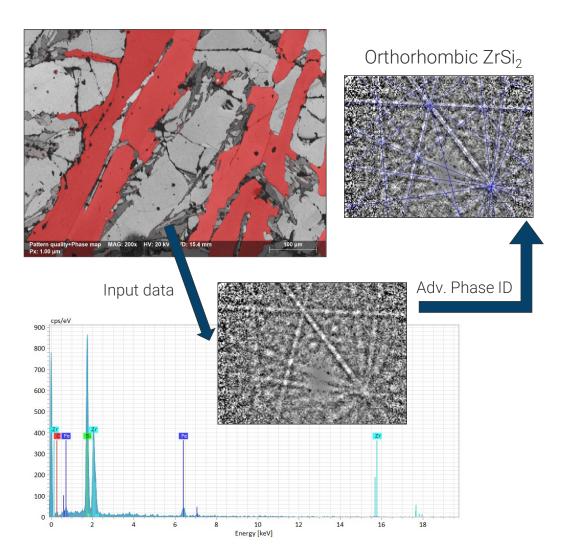
Raw phase map: Fe-Si composite material



Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials

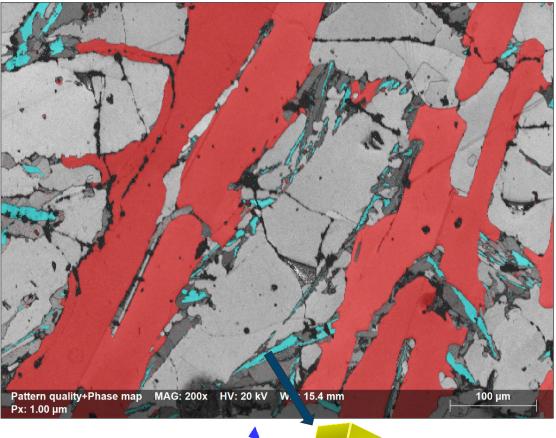
Advanced Phase ID:

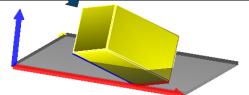
- Flexible semi-automatic search of phase candidates based on EDS spectrum (search through multiple databases with up to 900k phases)
- Ultra-fast indexing of all candidate phases (within seconds for a few thousand phase entries)
- Automatic classification based on best fit to experimental EBSP
- Multiple advanced features for improved identification, e.g. automatic search of pixels with similar chemistry, etc.





Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials





Ultra-fast map reanalysis:

- ESPRIT 2 is capable of reindexing speeds of up to 60,000 points/second (pps)
- Current map analyzed at 24,000pps with two phases
- Reindexing time: 13seconds
- Non-indexed areas of light gray levels are unknown phases
- Advanced Phase ID + Ultra-fast Reanalysis are applied iteratively until all present phases have been identified
- If necessary, the user can resave the map at any time and continue map completion at a latter time



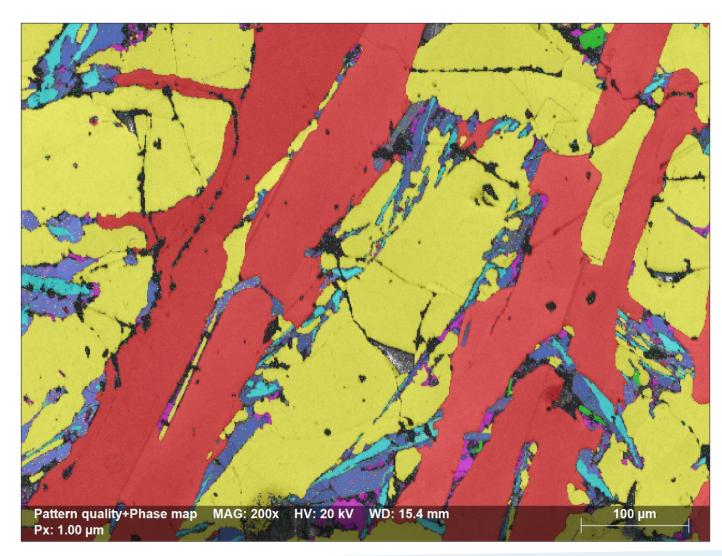
BRUKER

Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials

Ultrafast map reanalysis:

- Phase map after all phases have been identified:
 - 1. Silicon cubic (IT227)
 - 2. Ferdisilicide tetragonal (IT123)
 - 3. Titanium(II) iron silicide orthorhombic (IT55)
 - 4. Zirconium silicide orthorhombic (IT63)
 - 5. Calcium silicide trigonal (IT166)
 - 6. Zirconium iron silicide hexagonal (IT194)
- Map analyzed at ~6,500pps with six phases described above
- Reindexing time on a regular laptop: 48 seconds

NO DATA CLEANING!!

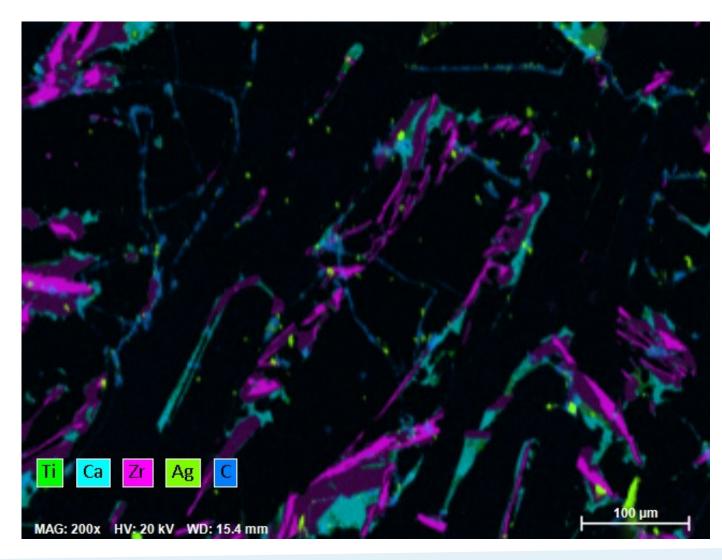




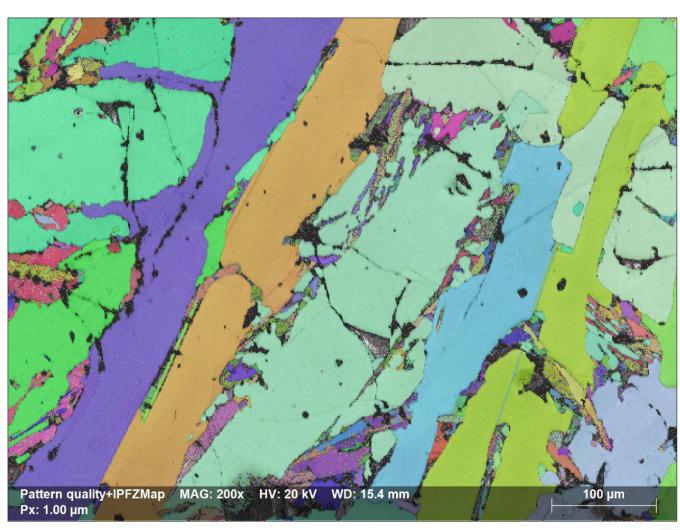
Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials

Simultaneously acquired EDS HyperMap:

- Each pixel contains a spectrum acquired in 20ms
- Total of 309k spectra
- Multitude of EDS based analysis types enabled by the full analytical power of ESPRIT 2



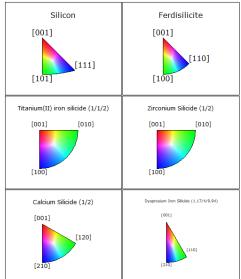
Simplicity Delivers Affordable Science Analysis of little-known multi-phase materials





Benefits:

- ESPRIT 2 offers the most powerful combination of EDS and EBSD techniques
- Minimized SEM use / maximized SEM throughput
- Map completion and data interpretation done offline without time constraints and on a separate computer





Simplicity Delivers Affordable Science Application example

Phase Identification & Distribution Analysis of Oxide Ceramics: ZnO

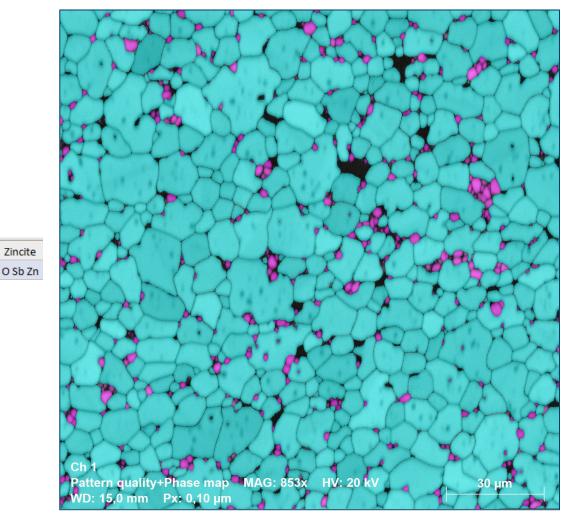
Simplicity Delivers Affordable Science Phase Identification & Distribution of Zn Oxides

Important parameters:

- EHT: 20kV
- Probe current: ~10 nA
- Step size: 100 nm
- Acquisition speed: 495 frames/second
- Total acquisition time: 80 min
- Map size: >2M points
- Pattern resolution: 180x135 pixels
- Phase fraction ZnO in blue (91%), Sb-ZnO in pink (4%).
- Porosity: 4,9 %



Pattern quality + Phase map



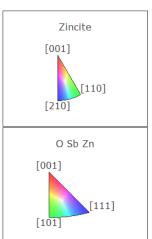
NO DATA CLEANING!

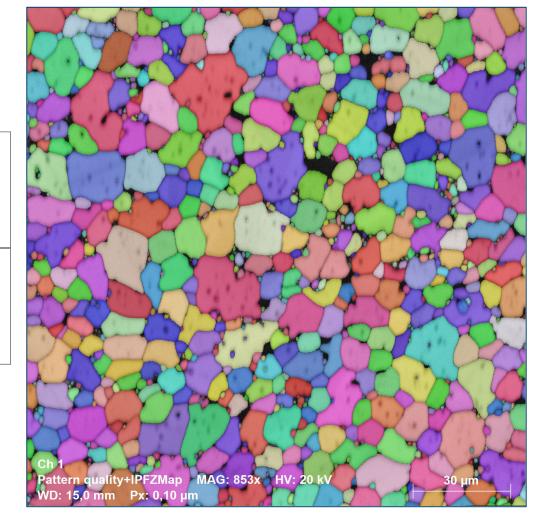
BRUKER

Simplicity Delivers Affordable Science Phase Identification & Distribution of Zn Oxides

Important parameters:

- EHT: 20kV
- Probe current: ~10 nA
- Step size: 100 nm
- Acquisition speed: 495 frames/second
- Total acquisition time: 80 min
- Map size: >2M points
- Pattern resolution: 180x135 pixels
- Phase fraction ZnO in blue (91%), Sb-ZnO in pink (4%).
- Porosity: 4,9 %.





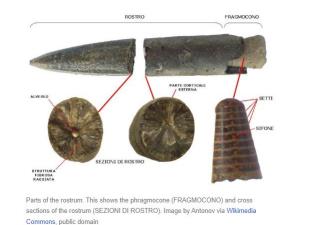
IPFx map

No data cleaning



Simplicity Delivers Affordable Science Application example

Microstructure and chemistry correlation for mineral characterization : Calcite (belemnite fossil)



British Geological Survey



Simplicity Delivers Affordable Science

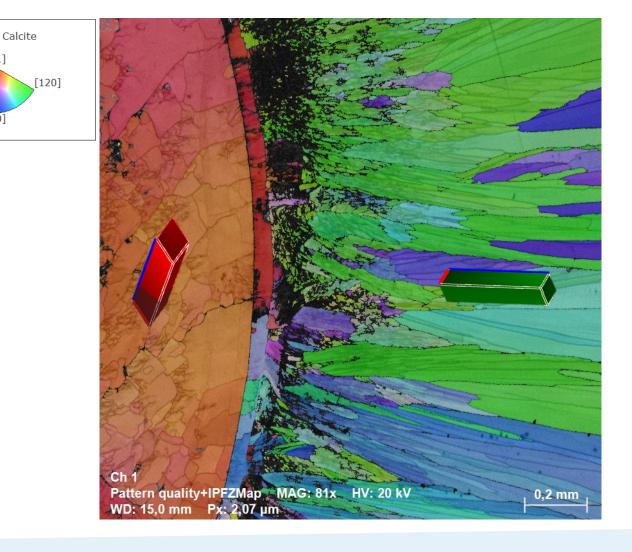
Microstructure and chemistry correlation for mineral characterization : Calcite

[001]

[210]

Parameters:

- EHT: 20kV
- Probe current: 15 nA
- Step size: 2 µm
- Acquisition speed: 122 frames/second
- Total acquisition time: 80 min
- Map size: 613k pixels
- Pattern resolution: 180x135 pixels
- Zero sol.: 13 %
- NO DATA CLEANING!
- C-coating too thick (~5nm is ideal)





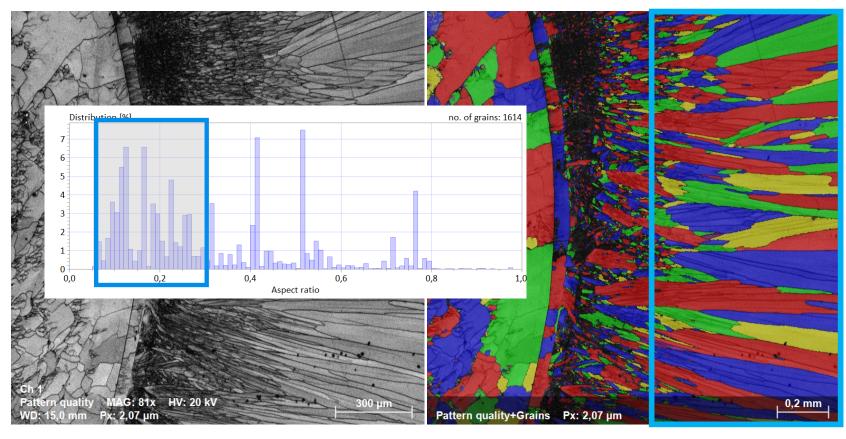
Simplicity Delivers Affordable Science

Microstructure and chemistry correlation for mineral characterization : Calcite

Pattern quality map

Parameters:

- EHT: 20kV
- Probe current: 15 nA
- Step size: 2 µm
- Acquisition speed: 122 frames/s
- Total acquisition time: 80 min
- Map size: 613k pixels
- Pattern resolution: 180x135 pixels
- Zero sol.: 13 %
- C-coating too thick



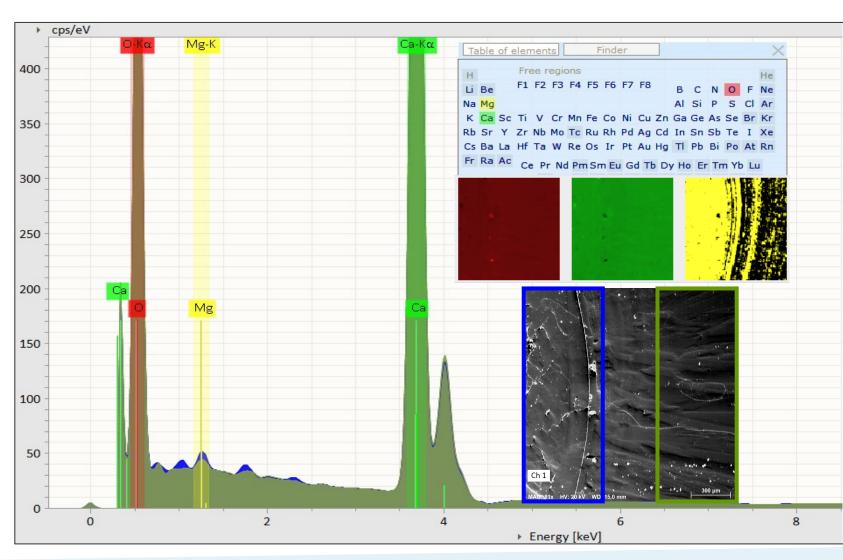


Pattern quality + Grain map

Simplicity Delivers Affordable Science

Microstructure and chemistry correlation for mineral characterization : Calcite

- Mg concentration can be correlated to the growth morphology of Calcite
- EDS spectrum acquired simultaneously with EBSD showing different Mg concentration between the inner and the outer shell/rostrum (with less than 5% at. in the richest region)







04 Summary

Innovation with Integrity



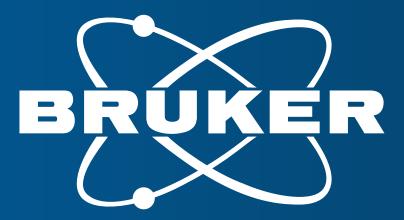
QUANTAX ED-XS Simplicity delivers affordable science

Efficient use of lab' resources by:

- Running routine analyses with QUANTAX ED-XS to relieve backlog on expensive FE-SEMs
- Checking sample preparation quality, before an EBSD session on an expensive FE-SEM
- Training of new users with much lower time/cost constraints
- Giving more time to entry level users for practicing EBSD & EDS data acquisition







Innovation with Integrity

info.bna@bruker.com

https://www.bruker.com/bna